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#### Key indicators

Single-crystal X-ray study  
T = 291 K  
Mean  $\sigma(C-C) = 0.003 \text{ \AA}$   
R factor = 0.033  
wR factor = 0.049  
Data-to-parameter ratio = 16.8

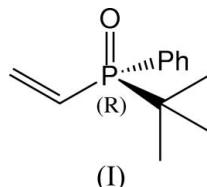
For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.

## (+)-(R)-(tert-Butylvinylphosphinoyl)benzene

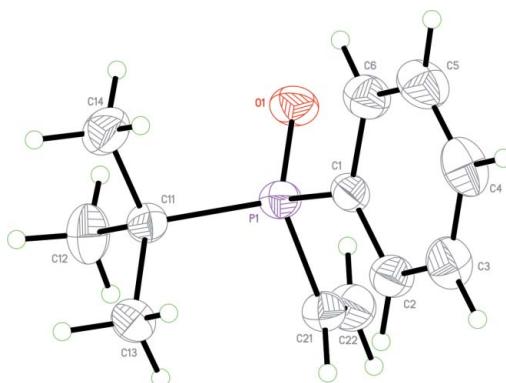
The chiral title compound,  $C_{12}H_{17}OP$ , with potential uses in asymmetric induction in homogeneous catalysed reactions, shows an *s-cis* conformation for the  $C=C-P=O$  unit, in common with related materials.

#### Comment

The title compound, (I), has been used as a substrate in a research project evaluating different routes to *P*-stereogenic *P,N*-ligands for homogeneous catalysis. It can also be used for Michael addition reactions (Maj, 2002), metathesis reactions (Demchuk *et al.*, 2003), and as a preligand for enantioselective transfer hydrogenation of ketones (Maj *et al.*, 1999).



In the solid state, the  $C_{22}=C_{21}-P_1=O_1$  unit of the molecule assumes an *s-cis* conformation with a torsion angle of  $-8.9(2)^\circ$  (Fig. 1). This conformational preference has been found without exception in the other three vinylphosphine oxides (Pietrusiewicz, Zablocka, Wieczorek & Brandi, 1991; Pietrusiewicz, Zablocka, Kuznicki *et al.*, 1991; Wieczorek, 1995), two vinylphosphine sulfides (Pietrusiewicz, Wieczorek *et al.*, 1991; Pietrusiewicz *et al.*, 1992), and one vinylphosphine selenide (Pietrusiewicz, Wieczorek *et al.*, 1991) studied by X-ray diffraction, and has also been considered important in the stereoselective 1,3-dipolar cycloaddition reactions of vinylphosphine chalcogenides with nitrones (Brandi *et al.*, 1989, 1991). The crystal structure of (I) also reveals that an *R*



**Figure 1**

The molecular structure of (I), with displacement ellipsoids drawn at the 30% probability level (arbitrary spheres for the H atoms).

configuration of the P atom correlates with dextrorotatory behaviour.

## Experimental

Compound (I) was prepared according to the method of Pietrusiewicz (1996). The *R* enantiomer was determined by chiral high performance liquid chromatography [chiralpak OJ, heptane–2-propanol (6:4),  $\lambda = 251$  nm,  $c = 1$  mg ml<sup>-1</sup>, injection volume = 0.5 µl] to be >99% ee.

### Crystal data

$C_{12}H_{17}OP$	$Z = 4$
$M_r = 208.23$	$D_x = 1.159 \text{ Mg m}^{-3}$
Orthorhombic, $P2_12_12_1$	Mo $K\alpha$ radiation
$a = 6.0852 (4) \text{ \AA}$	$\mu = 0.20 \text{ mm}^{-1}$
$b = 7.3750 (6) \text{ \AA}$	$T = 291 (1) \text{ K}$
$c = 26.598 (2) \text{ \AA}$	Column, colourless
$V = 1193.67 (15) \text{ \AA}^3$	$0.28 \times 0.10 \times 0.06 \text{ mm}$

### Data collection

Nonius KappaCCD diffractometer	2179 independent reflections
$\omega$ scans	1367 reflections with $I > 2\sigma(I)$
Absorption correction: none	$R_{\text{int}} = 0.046$
9543 measured reflections	$\theta_{\text{max}} = 25.4^\circ$

### Refinement

Refinement on $F^2$	$w = 1/[\sigma^2(F_o^2)]$
$R[F^2 > 2\sigma(F^2)] = 0.033$	$(\Delta/\sigma)_{\text{max}} < 0.001$
$wR(F^2) = 0.049$	$\Delta\rho_{\text{max}} = 0.21 \text{ e \AA}^{-3}$
$S = 0.82$	$\Delta\rho_{\text{min}} = -0.19 \text{ e \AA}^{-3}$
2179 reflections	Absolute structure: Flack (1983), 862 Friedel pairs
130 parameters	Flack parameter: -0.10 (8)
H-atom parameters constrained	

H atoms were placed in calculated positions, with C–H = 0.93–0.97 Å, and were refined as riding, with  $U_{\text{iso}}(\text{H}) = 1.5U_{\text{eq}}(\text{C})$  for methyl groups and  $1.2U_{\text{eq}}(\text{C})$  for other H atoms; the methyl groups were allowed to rotate but not to tip.

Data collection: *COLLECT* (Nonius, 1998); cell refinement: *DENZO* and *SCALEPACK* (Otwinowski & Minor, 1997); data reduction: *DENZO* & *SCALEPACK*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL-Plus* (Sheldrick, 1991); software used to prepare material for publication: *SHELXL97*, *PARST95* (Nardelli, 1995) and *PLATON* (Spek, 2003).

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